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Total Number of Pages: 02

M.Tech VLPE206

2nd Semester Regular / Back Examination 2015-16 EMERGING TOPICS IN IC DESIGN

Q.CODE:W932 Time: 3 Hours Max Marks: 70

Answer Question No.1 which is compulsory and any five from the rest. The figures in the right hand margin indicate marks. Assume values wherever missing

Q1 Answer the following questions:

(2 x 10)

- a) What are the drawbacks of JFET? Enlist some alternative configurations
- **b)** Find the maximum width of the depletion region for an ideal MOS capacitor on p-type Si in strong inversion given that the doping concentration is 10¹⁶ cm⁻³ and the relative dielectric constant is 11.8.
- c) Enlist some properties of ideal MIS systems.
- d) Calculate the cutoff frequency of a MOSFET given the following information: $L = 1\mu m$; n-channel device with a p-type substrate; $\mu'_n = 1200 \text{ cm}^2/\text{ (V s)}$; Z = 10 L; $V_T = 1.1 \text{ V}$; and $V_G = 5 \text{ V}$.
- e) Enlist the important features that arise in short-channel MOSFETs.
- f) Mention some key advantages of molecular materials.
- g) Differentiate between an Inverting type nMOS super buffer and an Non-inverting type nMOS super buffer
- **h)** Design an AOI Logic Circuit for the given SOP expression: $F = \bar{A}B\bar{C}D + BC\bar{D} + A\bar{B}$.
- i) Implement a 2:1 MUX using TG logic.
- j) What is hierarchy? How does it help in modular design?
- **Q2 a)** Discuss the behavior of a MESFET under different gate bias conditions with suitable illustrations. (5)
 - **b)** What is a MODFET? Give its basic device structure. What do you understand by 2 DEG?
- Q3 a) Draw and explain the Energy band diagram for an ideal MIS structure in equilibrium. (5)
 - **b)** Calculate the threshold voltage for a MIS structure given the following information. (5)

Let the semiconductor be p-type Si and the metal be Al. The doping concentration is $Na = 10^{17}$ cm⁻³, the oxide thickness is d = 10 nm, the work

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function difference $\phi_{ms} = -1.05$ V, the insulator surface charge density is $Q_i = 5 \times 10^{10} q$ C/cm², and $\kappa_i = 3.9$. Determine the depletion region width, W, the flat band voltage, V_{FB} and the threshold voltage, V_{T} .

- Consider an n-channel MOSFET with the following information: (10) $Na=5 \times 10^{16} \text{ cm}^{-3}$; $\mu'_n=500 \text{ cm}^2/(\text{V s})$; $\phi_{\text{ms}}=-0.96 \text{ V}$; $Q_i=5 \times 10^{10} \text{ q/cm}^2$; $Z=50 \mu \text{m}$; d=30 nm; $L=5 \mu \text{m}$; $n_i=10^{10} \text{ cm}^{-3}$; $\kappa_0=3.9$; $E_g=1.12 \text{ eV}$; $\kappa_s=11.9$. (i) Determine the drain current at a gate voltage VG=2 V and a drain voltage $V_D=1 \text{ V}$. (ii) Consider the case where the gate voltage is 3 V and the drain voltage in 4
- **Q5 a)** An n-channel MOSFET is to be scaled using constant voltage scaling. If the scaling factor λ is 0.7, determine the new device parameters given that the original device has $L = 1.0 \ \mu\text{m}$, $Z = 100 \ \text{mm}$, d (the oxide thickness) = 25 nm, $Na = 5 \times 10^{15} \ \text{cm}^{-3}$, and the applied voltage is 3 V.
 - b) Determine the thickness of the Si active layer in a partially depleted SOI device if the layer is only 50% depleted in equilibrium. Assume that the Schottky barrier height is 0.72 eV, the effective density of states within the conduction band is $N_c = 3.22 \times 10^{19}$ cm⁻³, and the doping concentration is 10^{16} cm⁻³. Assume that all of the donors are ionized.
- Q6 a) What do you mean by steering logic? Discuss design of any combinational circuit using steering logic. (5)
 - b) Compare between Semicustom and Full custom design strategies.

(5)

(5)

- Q7 a) Determine how the Poisson equation scales under: (5)
 - (i) Constant voltage scaling.
 - (ii) Quasi-constant voltage scaling.
 - b) Compare between CMOS and BICMOS logic.
- Q8 Write short notes on any two: (5 x 2)
 - a) CMOS static plots
 - b) Small Signal operation of MOSFETS
 - c) Carbon Nano tubes
 - d) Moletronics

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